

# PRODUCTION OF NEGATIVE IONS ON HOPG SAMPLE IN H2 BASED PLASMAS

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## "PHISIS" and his diagnostics

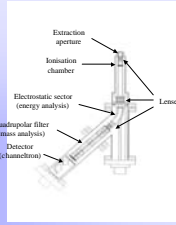
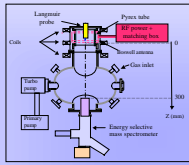


Fig. 3 : Sketch of the mass spectrometer with resolved energy (Hidden EQP 300)

Fig. 1 : photo and sketch of our helicon

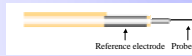


Fig. 2 : sketch of the Langmuir probe tip (Scientific Systems)

Langmuir probe (Fig.2) gives ( $V_p$ ,  $V_t$ ,  $T_e$ ,  $n_e$ ,  $n_i$ ) whether mass spectrometer (Fig.3) performs a local analysis of neutral species and ions with moreover an energy resolution

## Sample and Negative ion detection

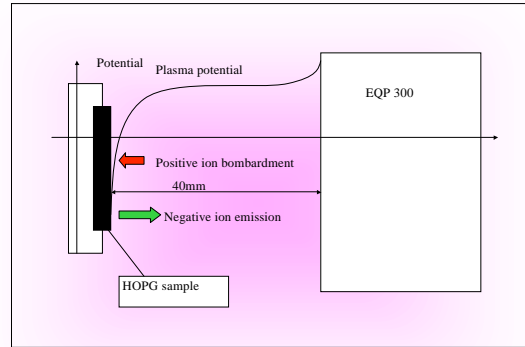


Figure 4 : negative ion collection by our spectrometer

## Example of IEDF for negative H- ions

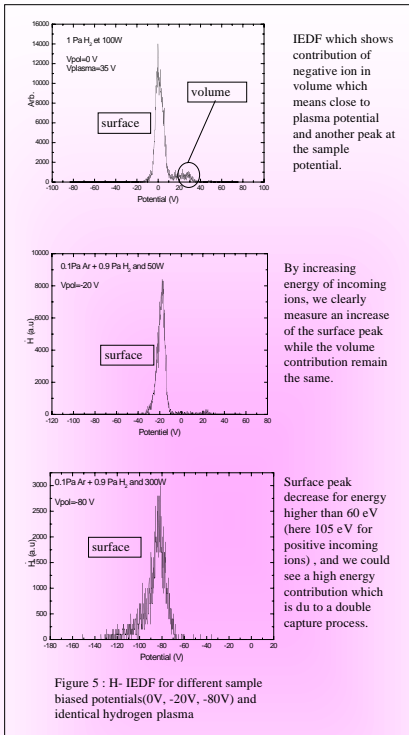
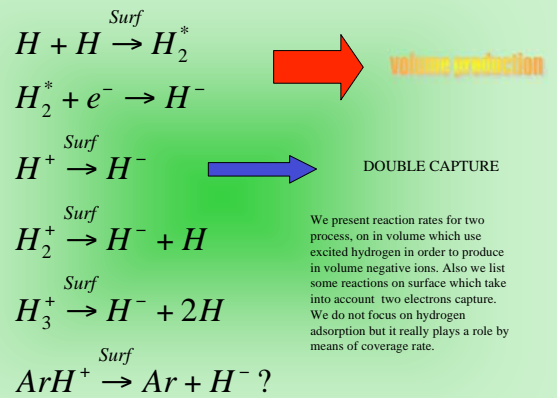


Figure 5 : H- IEDF for different sample biased potentials(0V, -20V, -80V) and identical hydrogen plasma

## Highest Chemical reaction rates



## CONCLUSION

The aim of this study was to improved negative ion production source, understand dust chemistry and also sheath stability.

We clearly show behavior of negative ion versus energy of the incoming ions and versus time. These result are still analyzed in order to make a small model which take into account the covering rate of hydrogen, atomic hydrogen, incoming positive ions ( $H^+$ ,  $H_2^+$ ,  $H_3^+$ ) and ( $Ar^+$ ,  $ArH^+$ ).

We show at first glance that the effect of argon does not have a huge influence on surface reactivity. The main effect of additional argon is to increase ion density by reducing ion-ion recombination.

A clear difference is seen on process by one electron and process by two.

By comparing volume and surface negative ion production, we show that surface is more efficient.

More investigations will be done to understand what happens on the HOPG surface when energy is higher than 70 eV, the question is still open.

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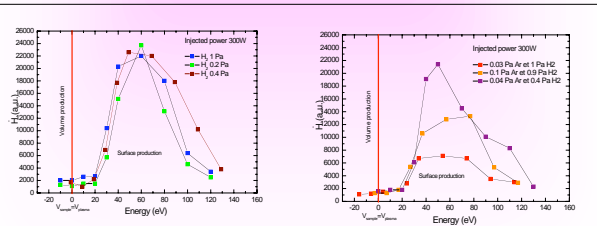


Figure 6 : H- surface peaks for incoming ion energy in hydrogen plasma

Figure 7 : H- surface peaks for incoming ion energy in mixture Argon hydrogen plasma